

ON Semiconductor®

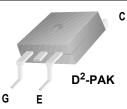
FGB20N60SFD-F085 600V, 20A Field Stop IGBT

Features

- · High current capability
- Low saturation voltage: V_{CE(sat)} = 2.2V @ I_C = 20A
- High input impedance
- · Fast switching
- Qualified to Automotive Requirements of AEC-Q101
- RoHS complaint

Applications

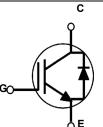
- Inverters, SMPS, PFC, UPS
- Automotive Chargers, Converters, High Voltage Auxiliaries



General Description

Using novel field-stop IGBT technology, ON Semiconductor's new series of field-stop IGBTs offers the optimum performance for automotive chargers, inverters, and other applications where low conduction and switching losses are essential.





Absolute Maximum Ratings

Symbol	Description		Ratings	Units	
V _{CES}	Collector to Emitter Voltage		600	V	
V _{GES}	Gate to Emitter Voltage		± 20	V	
I _C	Collector Current	@ T _C = 25°C	40	А	
ιC.	Collector Current	@ T _C = 100 ^o C	20	А	
I _{CM (1)}	Pulsed Collector Current	@ T _C = 25°C	60	А	
le.	Diode Forward Current	@ T _C = 25 ^o C	20	А	
F Di FM(1) Pt	Diode Forward Current	@ T _C = 100°C	10	A	
I _{FM(1)}	Pulsed Diode Maximum Forward Cu	ırrent	60	А	
P _D	Maximum Power Dissipation	@ T _C = 25 ^o C	208	W	
. D	Maximum Power Dissipation	@ T _C = 100°C	83	W	
TJ	Operating Junction Temperature		-55 to +150	°C	
T _{stg}	Storage Temperature Range		-55 to +150	°C	
TL	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 seconds		300	°C	
Thermal C	haracteristics				
Symbol	Paramete	r	Ratings	Units	
$R_{\theta JC}(IGBT)_{(2)}$	Thermal Resistance, Junction to Ca	se	0.6	°C/W	
Raug(Diode)	Thermal Resistance Junction to Ca	99	2.6	°C/W	

			°C/W	
Symbol	Parameter	Тур.	Units	
$R_{\theta JC}$ (Diode)	Thermal Resistance, Junction to Case	2.6	°C/W	
$R_{\theta JC}(IGBI)_{(2)}$	Inermal Resistance, Junction to Case	0.6	°C/W	

				Packaging			Max	k Qty
Device Marking		Device	Package	Туре	Qty p	er Tube	per Box	
FGB20N	FGB20N60SFD FGB20N60SFD-F085		TO-263	Tube	5	0ea		
=lectric	al Cha	racteristics of the					I	
Symbol		Parameter	-	conditions	Min.	Тур.	Max.	Units
-	toriotico							
Off Charac BV _{CES}	1	to Emitter Breakdown Voltage		: 250uA	600	_	_	V
ΔBV_{CES} ΔT_{J}		ure Coefficient of Breakdown		$V_{GE} = 0V, I_{C} = 250\mu A$ $V_{GE} = 0V, I_{C} = 250\mu A$		0.79	-	V/ºC
I _{CES}	-	Cut-Off Current	V _{CE} = V _{CES} , V	V _{CE} = V _{CES} , V _{GE} = 0V		-	250	
	E3			BVCES, 150°C	-	-	250	μA
I _{GES}	G-E Leak	age Current	V _{GE} = V _{GES} , V	-	_	-	±400	nA
					1	1		I
On Charac V _{GE(th)}	1	shold Voltage	I _C = 250μA, V _{CE} = V _{GE}		4.0	4.8	6.5	V
• GE(th)	5 2 1110		I _C = 200μA, V _{GE}			2.2	2.85	V
V _{CE(sat)}	Collector	to Emitter Saturation Voltage			-	2.4	-	v
Dynamic C	haracteris	atics				<u>. </u>		1
C _{ies}	Input Cap				_	940	1250	pF
C _{oes}		apacitance	V _{CE} = 30V, V _{GE} = 0V, f = 1MHz		-	110	146	pF
C _{res}	Reverse	Transfer Capacitance			-	40	53	pF
					I	1 1		I
Switching		Delay Time			-	10	13	200
t _{d(on)} +	Rise Time				-	10	21	ns ns
t _r		- Delay Time		00.4		90	120	ns
t _{d(off)}	Fall Time		V _{CC} = 400V, I ₀ R _G = 10Ω, V _G	_C = 20A, _F = 15V,	-	24	36	ns
t _f E _{on}		Switching Loss	Inductive Load	, т _с = 25°С	-	0.31	0.41	mJ
E _{off}		Switching Loss	-		_	0.13	0.21	mJ
E _{ts}		tching Loss	-		_	0.44	0.59	mJ
t _{d(on)}		Delay Time			-	12	16	ns
t _r	Rise Time	•	-		_	16	21	ns
t _{d(off)}		Delay Time	V _{CC} = 400V, I ₀	~ = 20A	-	95	126	ns
t _f	Fall Time		R _G = 10Ω, V _G	_E = 15V,	-	28	43	ns
E _{on}	Turn-On	Switching Loss	Inductive Load	d, T _C = 125ºC	_	0.45	0.60	mJ
E _{off}		Switching Loss			-	0.21	0.38	mJ
E _{ts}		tching Loss	-		-	0.66	0.88	mJ
Q _g	Total Gate	0			-	63	95	nC
Q _{ge}		mitter Charge	V _{CE} = 400V, I _C	_C = 20A,	-	7	11	nC
3~	1	•	– V _{GE} = 15V					

Electrical Characteristics of the Diode $T_{c} = 25^{\circ}C$ unless otherwise noted								
Symbol	Parameter	Test Condition	Min.	Тур.	Max	Units		
V _{FM}	Diode Forward Voltage	I _F = 10A	T _C = 25°C	-	1.9	2.5	V	
			T _C = 125°C	-	1.7	-		
t _{rr}	Diode Reverse Recovery Time		T _C = 25°C	-	111	-	ns	
			T _C = 125°C	-	204	-		
Q _{rr}	Diode Reverse Recovery Charge		T _C = 25°C	-	174	244	nC	
			T _C = 125 ^o C	-	463	-		

Notes: 1: Repetitive rating: Pulse width limited by max. junction temperature

2:Rthjc for D2-PAK: according to Mil standard 883-1012 test method.

Rthja for D2-PAK: according to JESD51-2, test method environmental condition and JESD51-3, low effective thermal conductivity test board for leaded surface mount package. thermal measurements. JESD51-2: Integrated Circuits Thermal Test Method Environmental Conditions - Natural Convection (Still Air).

Typical Performance Characteristics



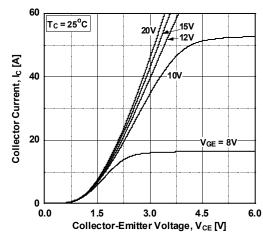


Figure 3. Typical Saturation Voltage Characteristics

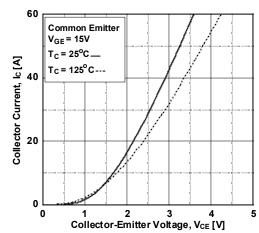


Figure 5. Saturation Voltage vs. Case Temperature at Variant Current Level

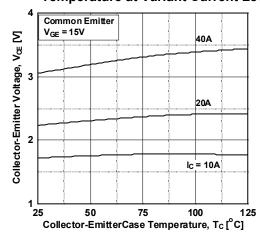


Figure 2. Typical Output Characteristics

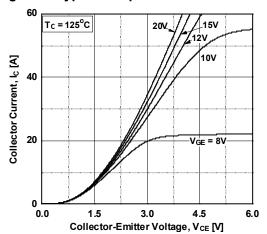


Figure 4. Transfer Characteristics

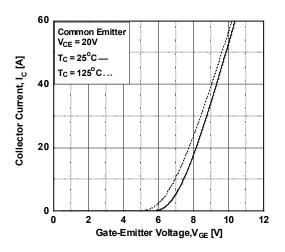
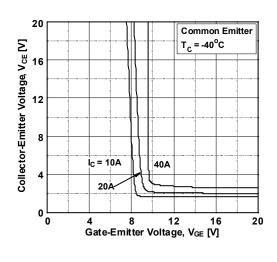
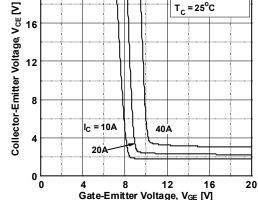


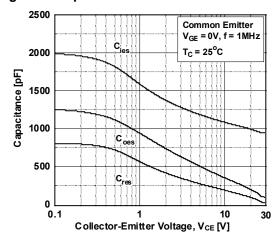
Figure 6. Saturation Voltage vs. V_{GE}



Typical Performance Characteristics Figure 7. Saturation Voltage vs. V_{GE}









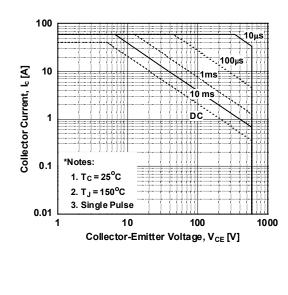


Figure 8. Saturation Voltage vs. V_{GE}

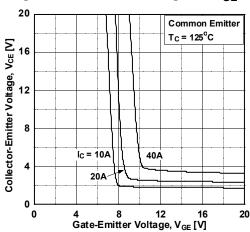


Figure 10. Gate charge Characteristics

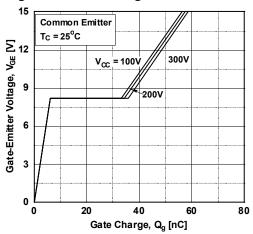
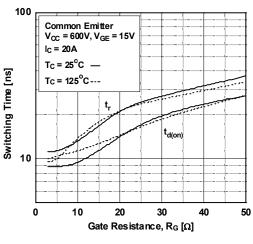
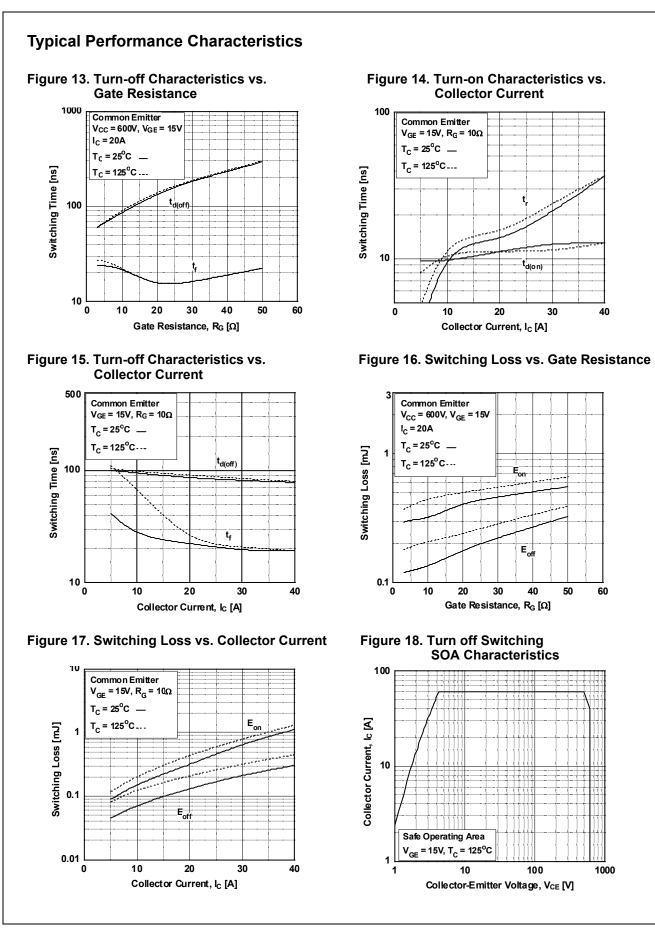
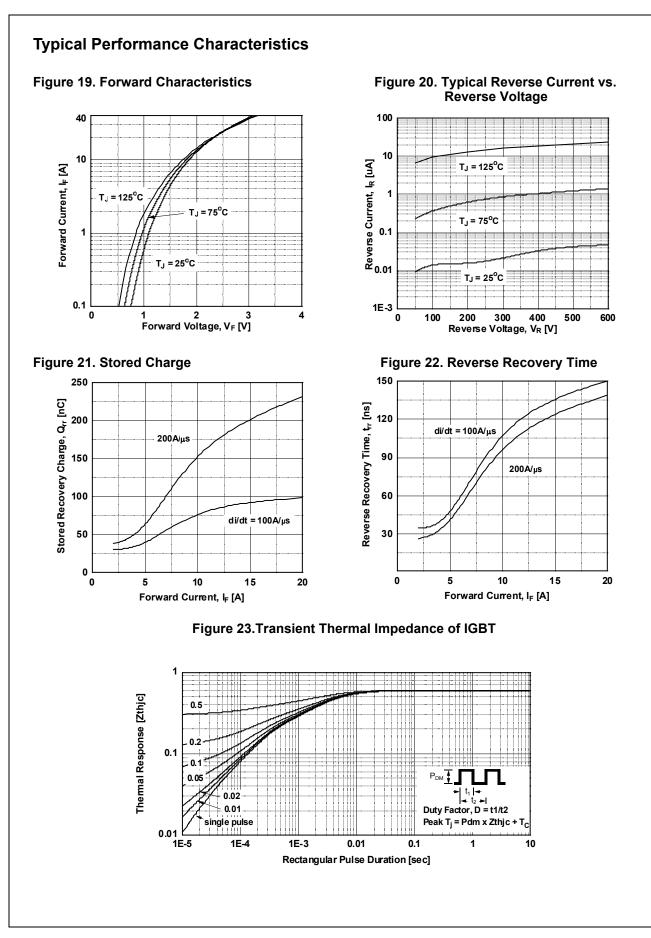
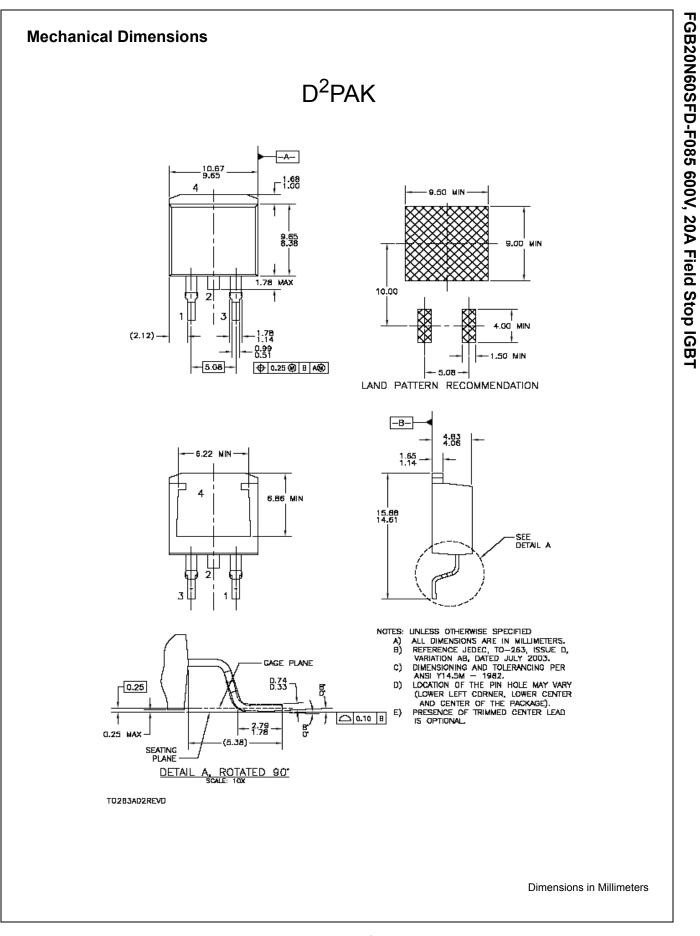


Figure 12. Turn-on Characteristics vs. Gate Resistance









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